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AN - 1984-016591 [03]

AP - SU19813355509 19811120

CPY - CRYS-R

DC - S03

FS - EPI

IC - G01N23/20

IN - KHEIKER D M; POPOV A N; ZANEVSKII Y U V

MC - S03-E06C

PA - (CRYS-R) CRYSTALLOGRAPHY INS

PN - SU1004834 A 19830315 DW198403 003pp

PR - SU19813355509 19811120

XIC - G01N-023/20

XP - N1984-012280

AB - SU1004834 X-ray diffractometer is designed for structural investigation of crystals and claims better resolving power in recording diffraction pictures. Source (1) of X-ray illumination irradiates crystal (5) for formation of an image on plane two-coordinate detector (2) with longitudinal movement. The crystal holder (4) is held on goniometer (3) and the radiation source (1) is given angular movement by bracket (6) attached on rotary base (7). A monochromatised and collimated beam is directed on to the crystal to provide the diffraction picture on detector (2). The measurement of X-ray reflectors is done by continuous scanning round the vertical axis.

- Optimum pictures are obtained by adjustment in the other axes. A helium buffer (8) is interposed to minimise absorption of the radiation in air. The geometry of the system affords less divergence and better resolution with crystals with large elementary cells.

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- (3pp Dwg.No.1/1)

IW - IMPROVE X-RAY DIFFRACTED SOURCE DIRECT CRYSTAL CAPABLE TRIAXIAL ROTATING FORM TWO COORDINATE PLOT THROUGH HELIUM BUFFER

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INW - KHEIKER D M; POPOV A N; ZANEVSKII Y U V

NC - 001

OPD - 1981-11-20

ORD - 1983-03-15

PAW - (CRYS-R) CRYSTALLOGRAPHY INS

TI - Improved X-ray diffractometer - has source directed on to crystal capable of triaxial rotation to form two-coordinate plot through helium-buffer